

**Notice of References Cited**

Application/Control No.

10/551,437

Applicant(s)/Patent Under  
Reexamination  
TOGAWA ET AL.

Examiner

Dwan A. Gerido, Ph.D.

Art Unit

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*	B	US-2002/0177772	11-2002	Altman et al.	600/431
*	C	US-3,837,376	09-1974	Brown et al.	141/1
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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